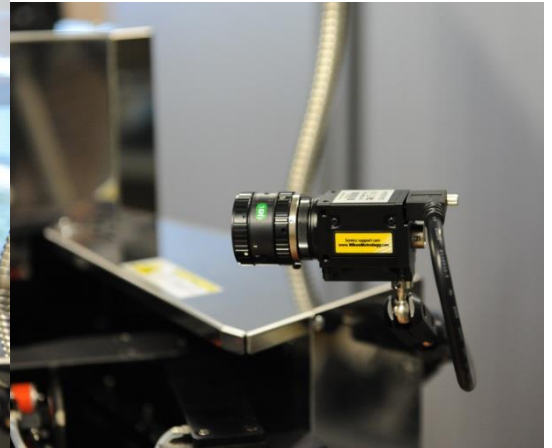
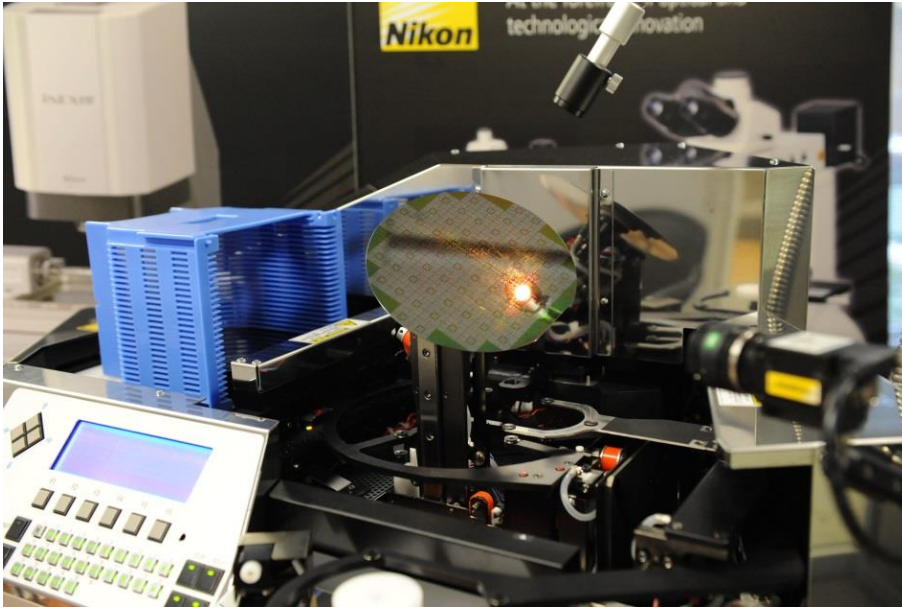




# Application Focus

## Wafer loader for IC inspection microscopes



### NWL200

Introduction - Recently the demand for taking pictures from a complete wafer. We can now offer a custom made solution. Because of the partnership between several strategic partners.




#### Customer's challenges:

- Macro inspection of complete wafer
- Locate defect on the complete wafer
- Locate impurity on the complete wafer

#### Our solution

##### Products



- Camera : Images Source 
- Lens : Opto Engineering 
- Stand : Opto 
- Software : NIS-elements 